


<b>Search Notes</b> 	<b>Application/Control No.</b> 10584307	<b>Applicant(s)/Patent Under Reexamination</b> TANAKA ET AL.
	<b>Examiner</b> Arnberg, Megan	<b>Art Unit</b> 1796

### SEARCHED

Class	Subclass	Date	Examiner
428	413	Jan. 25, 2008	MCA
428	413	Sept. 9, 2008	MCM

### SEARCH NOTES

Search Notes	Date	Examiner
Inventor name search -see printout	Jan. 25, 2008	MCA
EAST (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT) - see printout	Jan. 25, 2008	MCA
STN structure search -see printout	Jan. 25, 2008	MCA
Updated Inventor name search -see printout	Sept. 9, 2008	MCM
Updated EAST search -see printout	Sept. 9, 2008	MCM
Updated STN structure search -see printout	Sept. 9, 2008	MCM

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

/M. M./  
Examiner, Art Unit 1796